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Distr-	L		Schafer et al. (1991); "Transcription of single molecules of RNA polymerase observed by light microscopy;" NATURE 352, PAGE 444												
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Dist	N		K. K. Likharev; "Single-electron devices and their applications;" PROC. OF THE IEEE VOL. 87 NO. 4, APRIL 1999, PAGE 606												
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